S302

4PP measurement stand

Electrical resistivity measurement is an essential step in the characterization of conductive and semiconducting materials. This manual 4-point probe stand offers a simple, reliable, and precise solution for determining the resistivity of various samples, such as thin films, wafers, or bulk materials.

Based on the 4-point probe method, this device eliminates the influence of contact resistance, thus ensuring more accurate measurements than two-electrode techniques. The operator manually positions the probes on the sample surface, providing great flexibility and adaptability to different geometries. Compact and ergonomic, this stand is particularly well-suited for research laboratories, educational environments, and quality control in production. It is a robust tool for rapid measurements while maintaining excellent repeatability.

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This stand includes a height adjustment for the 4-point head, allowing for the measurement of samples of varying thicknesses.

It also incorporates a contact/non-contact switch, enabling repeatability measurements without touching at the height.

Its chuck is manually moved to the desired measurement location, and its Delrin coating provides electrical insulation and protects the back of the sample. The chuck is available in 100 mm and 150 mm size.

The connection is made on the rear panel, with four banana plugs for connecting your source and measurement device.

The four-point probe head is equipped with a SubD9 quick connector, allowing for rapid removal and reinstallation on the stand.

A contact switch is linked to the contact lever, preventing continuous current flow to the probes (in manual operation) and thus eliminating electrical arcing when the probes make contact with the layer being measured.

Configurator:

S302-	
4	For 4’’ (100mm) wafer
6	For 6” (150mm) wafer

Specifications:

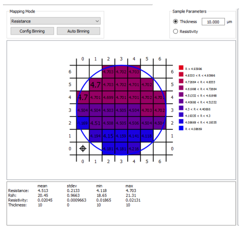
Wafer size	4” (100mm) or 6” (150mm)
Mouvement	Manual
Chuck material	Delrin
Wafer holding	No
Max height adjustment	40mm
Contact/no contact height	4mm
Probe head capabilities	SP4 and HT4
Probe head quick mount	Yes
Probe head connexion	SubD9
Stand connexion	4 x banana plugs (I+, I-, V+, V-)
Temperature	Not available
Size (w x l x h)	360 x 200 x 230mm
Weight	6kg

Related products

4PP probe head

SMU devices

Software



Mapping Mode: Resistance

Sample Parameters: ● Thickness 10.000 µm ○ Resistivity

```
             mean      stdev       min       max
Resistance:  4.513     0.2133      4.118     4.703
Rsh:         20.45     0.9663      18.65     21.31
Resistivity: 0.02045   0.0009663   0.01865   0.02131
Thickness:   10        0           10        10
```

Thermal meas.

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